# Application/Control No. Applicant(s)/Patent Under Reexamination SNYDER ET AL. Examiner Ba Huynh Applicant(s)/Patent Under Reexamination SNYDER ET AL. Page 1 of 1

# Notice of References Cited

### **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,198,906	03-2001	Boetje et al.	455/3.01
	В	US-			
	С	US-			
	D	US-			
	Ε	US-			
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## **NON-PATENT DOCUMENTS**

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